

Chuan C. Chang
Patents, PhD Thesis, Articles, & Abstracts
Partial List

Patents

- (7) [Nitrided Silicon Dioxide Layers for Semiconductor Integrated Circuits, Nov. 18, 1986](#)
Patent 4,623,912
- (6) [Method of Fabricating MOS Field Effect Transistors, Apr. 13, 1982](#)
Patent 4,144,634
- (5) [Method of Cleaning Test Probes, Feb. 9, 1982](#)
Patent 4,314,855
- (4) [Gold-Tin-Gold Ohmic Contact to N-Type Group III-V Semiconductors, Dec. 18, 1979](#)
Patent 4,179,534
- (3) [Fabrication of Gallium Arsenide MOS Devices, Mar. 20, 1979](#)
Patent 4,144,634
- (2) [Technique for Preparation of Stoichiometric III-V Compound Semiconductor Surfaces, May 31, 1977](#)
Patent 4,026,741
- (1) [Light Sensitive Storage Device Including Diode Array and Method for Producing the Array, Aug. 29, 1972](#)
Patent 3,687,745

Publications

(1) Low Energy Electron Diffraction

http://rsi.aip.org/resource/1/rsinak/v42/i2/p189_s1?isAuthorized=no
LEED Optics as Electron Mirror Microscope

http://jap.aip.org/resource/1/japiau/v39/i12/p5570_s1?isAuthorized=no
LEED Studies of the (0001) Face of α -Alumina

<http://jes.ecSDL.org/content/115/4/354.abstract>
LEED Studies, Adsorption of Carbon Monoxide on the Tungsten (112) Face

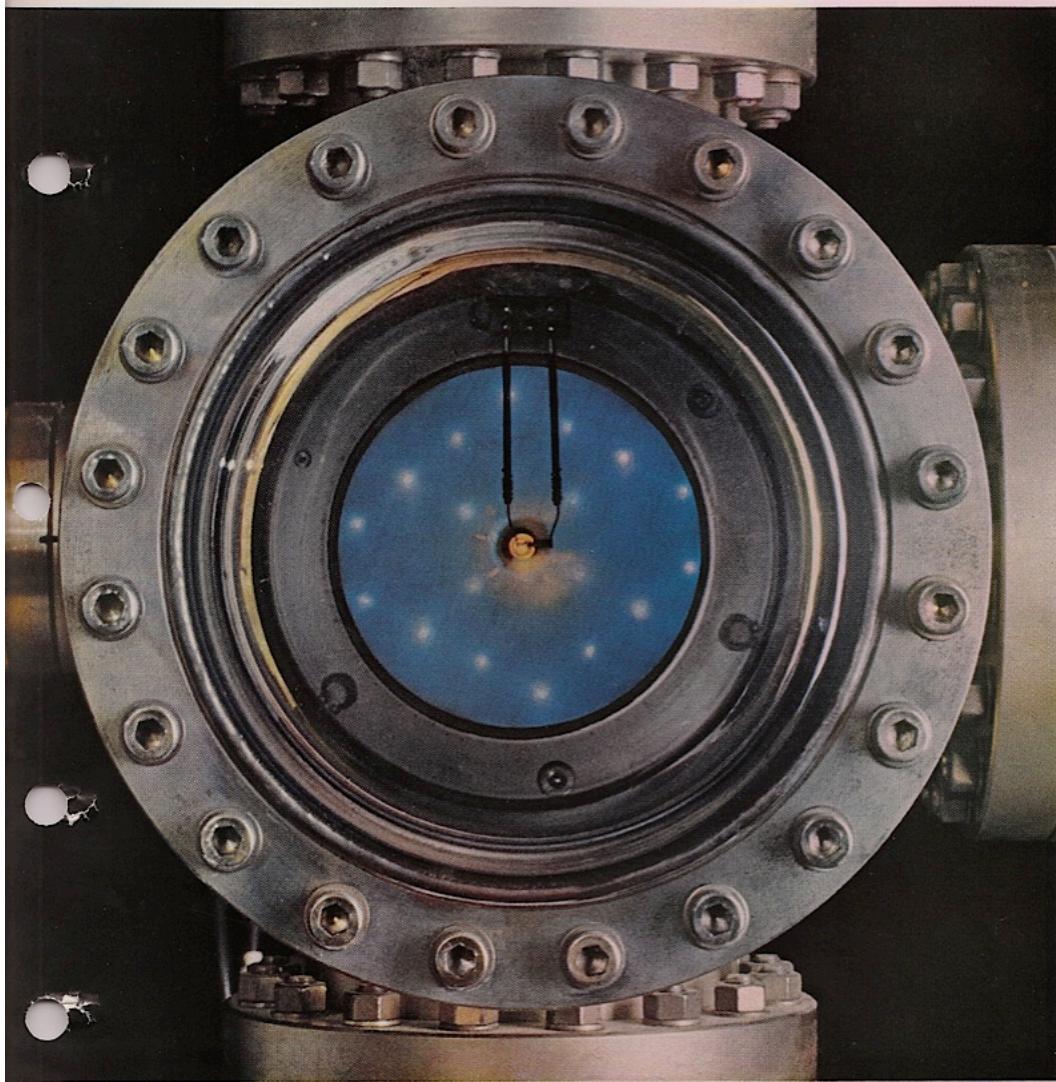
(2) PhD Thesis (large file): "Low Energy Electron Diffraction Studies, Adsorption of Oxygen, Carbon-Monoxide and Nitrogen on the Tungsten (112) Face".

<http://adsabs.harvard.edu//abs/1967PhDT.....55C>

The instrument I built for this thesis (with Varian Associates) was featured on the cover of Scientific American (next page).

Not shown are the vacuum pumping system consisting of two Vacion pumps, a mercury diffusion pump, a liquid nitrogen cryo-pump backed by a mechanical pump, and a baking hood that can heat the entire system to over 200 degrees C, thus achieving one of the highest vacuums ever produced on earth.

SCIENTIFIC AMERICAN



THE STRUCTURE OF CRYSTAL SURFACES

SIXTY CENTS

March 1965

Above Photo: Low Energy Electron Diffraction apparatus: The blue screen is a phosphor that lights up when hit by electrons; the white spots are electrons representing the reciprocal lattice of the single crystal tungsten welded between the vertical rods.

The chamber is under ultra-high vacuum comparable to that on the moon. A narrow beam of electrons is shot out of a gun (center bright object) at a known energy and are backscattered from the crystal towards the screen; instead of a uniformly bright screen, you get spots because electrons are waves and “diffract” from the tungsten crystal in a pattern that can be calculated exactly. This is the original phenomenon that led to the discovery of the wave nature of matter and a Nobel prize. How a SINGLE electron “sees” so many atoms at once and diffracts remains a mystery to this day; diffraction is a single-particle event.

Since we know the wavelength of the electron from its energy, the distance between spots tells us the distance between tungsten atoms and the pattern of spots tells us how the tungsten atoms are arranged on the surface. The size of the spots, which is much larger than the diameter of the electron beam, tells us how many tungsten atoms each electron “sees”; in this case, over 10,000 surface atoms. Since most of the electrons are scattered by just one or two layers of atoms, we can now “see” just the topmost atom layer of a surface -- we have atomic depth resolution!

(3) Auger Spectroscopy

http://ieeexplore.ieee.org/xpl/freeabs_all.jsp?arnumber=4846849

Intensity variations in Auger spectra caused by diffraction

<http://www.sciencedirect.com/science/article/pii/003960287190210X>

Auger Electron Spectroscopy

[*Auger Electron Spectroscopy in Characterization of Solid Surfaces*](#)

(4) Semiconductors

[*Semiconductors, Fabrication and Characterization, in Encyclopedia of Semiconductor Technology*, Wiley, 1984](#)

<http://jes.ecSDL.org/content/124/6/922.abstract>

Anodic Oxide on GaAs: Quantitative Chemical Depth Profiles Obtained Using Auger Spectroscopy and Neutron Activation Analysis

<http://www.sciencemag.org/content/245/4916/391.abstract>

GaAs Clusters in the Quantum Size Regime: Growth on High Surface Area Silica by Molecular Beam Epitaxy

http://ieeexplore.ieee.org/xpl/freeabs_all.jsp?arnumber=4952743

Chemical preparation of GaAs surfaces and their characterization by Auger electron and x-ray photoemission spectroscopies

http://ieeexplore.ieee.org/xpl/freeabs_all.jsp?arnumber=5081499

Co/GaAs interfacial reactions

http://ieeexplore.ieee.org/xpl/freeabs_all.jsp?arnumber=4859117

Electronic passivation of GaAs surfaces through the formation of arsenic–sulfur bonds

http://ieeexplore.ieee.org/xpl/freeabs_all.jsp?arnumber=5086280

Enhanced electronic properties of GaAs surfaces chemically passivated by selenium reactions

http://ieeexplore.ieee.org/xpl/freeabs_all.jsp?arnumber=4856871

Epitaxial growth of GaAs/NiAl/GaAs heterostructures

http://ieeexplore.ieee.org/xpl/freeabs_all.jsp?arnumber=5101156

Interdiffusions in thin-film Au on Pt on GaAs (100) studied with Auger spectroscopy

http://ieeexplore.ieee.org/xpl/freeabs_all.jsp?arnumber=4861404

Ni-InP reaction: Formation of amorphous and crystalline ternary phases

http://ieeexplore.ieee.org/xpl/freeabs_all.jsp?arnumber=4856912

NiAl/n-GaAs Schottky diodes: Barrier height enhancement by high-temperature annealing

http://ieeexplore.ieee.org/xpl/freeabs_all.jsp?arnumber=4956076

Silicon-on-Sapphire Epitaxy by Vacuum Sublimation: LEED–Auger Studies and Electronic Properties of the Films

http://ieeexplore.ieee.org/xpl/freeabs_all.jsp?arnumber=4966237

Structure and stability of passivating arsenic sulfide phases on GaAs surfaces

http://ieeexplore.ieee.org/xpl/freeabs_all.jsp?arnumber=4849348

Thermal oxidation of hafnium silicide films on silicon

http://ieeexplore.ieee.org/xpl/freeabs_all.jsp?arnumber=1478461

Transmission electron microscopy of cross sections of large scale integrated circuits

http://prl.aps.org/abstract/PRL/v57/i2/p249_1

Unusually Low Surface-Recombination Velocity on Silicon and Germanium Surfaces

http://avspublications.org/jvsta/resource/1/jvtad6/v6/i3/p1456_s1?isAuthorized=no

Studies of Co/Ga_{1-x}Al_xAs interfaces fabricated in ultrahigh vacuum

<http://jes.ecSDL.org/content/127/8/1787.short>

The Growth and Characterization of Very Thin Silicon Dioxide Films

<http://jes.ecSDL.org/content/126/11/1951.abstract?related-urls=yes&legid=jes;126/11/1951>

Effect of Growth Parameters on the CVD of Boron Nitride and Phosphorus-Doped Boron Nitride

<http://ieeexplore.ieee.org/xpl/login.jsp?tp=&arnumber=109528&url=http%3A%2F%2Fieeexplore.ieee.org%2Fiel1%2F2220%2F3327%2F00109528.pdf%3Farnumber%3D109528>

Dry-etching process for the fabrication of optoelectronic gratings in III-V substrates

(5) Superconductors

http://ieeexplore.ieee.org/xpl/freeabs_all.jsp?arnumber=4856026

Pulsed laser etching of high T_c superconducting films

http://jap.aip.org/resource/1/japiau/v61/i11/p5089_s1?isAuthorized=no

Auger electron spectroscopy, transmission electron microscopy, and scanning electron microscopy studies of Nb/Al/Nb Josephson junction structures

http://ieeexplore.ieee.org/xpl/freeabs_all.jsp?arnumber=4857506

As-deposited high T_c and J_c superconducting thin films made at low temperatures

http://ieeexplore.ieee.org/xpl/freeabs_all.jsp?arnumber=5085237

Doping mechanism in Bi(Pb)-Sr-Ca-Cu-O superconductors

http://ieeexplore.ieee.org/xpl/freeabs_all.jsp?arnumber=4857443

Low-temperature preparation of high T_c superconducting thin films

http://ieeexplore.ieee.org/xpl/freeabs_all.jsp?arnumber=4858680

Microstructure of in situ epitaxially grown superconducting Y-Ba-Cu-O thin films

http://ieeexplore.ieee.org/xpl/freeabs_all.jsp?arnumber=4857684

Nature of the pulsed laser process for the deposition of high T_c superconducting thin films

http://ieeexplore.ieee.org/xpl/freeabs_all.jsp?arnumber=4858794

Optical spectroscopy: An in situ diagnostic for pulsed laser deposition of high T_c superconducting thin films

http://ieeexplore.ieee.org/xpl/freeabs_all.jsp?arnumber=4846419

Plasma oxidation of aluminum film on GaAs—A study by Auger spectroscopy and transmission electron microscopy

http://ieeexplore.ieee.org/xpl/freeabs_all.jsp?arnumber=4861876

Structural perfection of Y-Ba-Cu-O thin films controlled by the growth mechanism

http://ieeexplore.ieee.org/xpl/freeabs_all.jsp?arnumber=5082843

Substrate effects on the properties of Y-Ba-Cu-O superconducting films prepared by laser deposition

http://apl.aip.org/resource/1/applab/v57/i17/p1814_s1?isAuthorized=no

Origin of surface roughness for c-axis oriented Y-Ba-Cu-O superconducting films

http://apl.aip.org/resource/1/applab/v56/i4/p400_s1?isAuthorized=no

Superlattices of Y-Ba-Cu-O/Y_y-Pr_{1-y}-Ba-Cu-O grown by pulsed laser deposition

http://apl.aip.org/resource/1/applab/v53/i6/p517_s1?isAuthorized=no

Smooth high T_c Y₁Ba₂Cu₃O_x films by laser deposition at 650 °C

http://apl.aip.org/resource/1/applab/v55/i11/p1138_s1?isAuthorized=no

Ferrimagnetic rare-earth orthoferrites: A new, magnetic substrate for the growth of epitaxial Y-Ba-Cu-O thin films

(6) Li Batteries

<http://www.readcube.com/articles/10.1002%2Fchin.199243023>

Low Temperature LiMn₂O₄ Spinel Films for Secondary Lithium Batteries

(7) Telephone Central Office

<http://jes.ecSDL.org/content/142/9/3157.abstract>

Monitoring of In Situ Corrosion Rates in a Telephone Switching Office in Burbank, California

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